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APPLICATION NO.	FILI	NG DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/659,435	09	/11/2003	Cem Basceri	M4065.0528/P528-A	4094	
24998	7590	03/28/2005		EXAMINER		
DICKSTEI 2101 L Stree		O MORIN & OS	PERT, EVAN T			
Washington		7	ART UNIT	PAPER NUMBER		
				2826		
				DATE MAILED: 03/28/2005		

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)					
	10/659,435	BASCERI ET AL.					
Office Action Summary	Examiner	Art Unit					
	Evan Pert	2826					
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply							
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a reply If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days fill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONEI	ely filed s will be considered timely. the mailing date of this communication. O (35 U.S.C. § 133).					
Status							
2a) ☐ This action is <b>FINAL</b> . 2b) ☑ This 3) ☐ Since this application is in condition for alloware							
Disposition of Claims		•					
<ul> <li>4)  Claim(s) 65-103 is/are pending in the application.</li> <li>4a) Of the above claim(s) is/are withdrawn from consideration.</li> <li>5)  Claim(s) 92-103 is/are allowed.</li> <li>6)  Claim(s) 65,66,74,75 and 84-88 is/are rejected.</li> <li>7)  Claim(s) 67-73,76-83 and 89-91 is/are objected to.</li> <li>8)  Claim(s) are subject to restriction and/or election requirement.</li> </ul>							
Application Papers							
9) ☐ The specification is objected to by the Examine 10) ☑ The drawing(s) filed on 11 September 2003 is/a Applicant may not request that any objection to the Replacement drawing sheet(s) including the correction 11) ☐ The oath or declaration is objected to by the Examine 11.	re: a)⊠ accepted or b)⊡ object drawing(s) be held in abeyance. See don is required if the drawing(s) is obj	ected to. See 37 CFR 1.121(d).					
Priority under 35 U.S.C. § 119		•					
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the priority application from the International Bureau * See the attached detailed Office action for a list of	s have been received. s have been received in Application ity documents have been received (PCT Rule 17.2(a)).	on No In this National Stage					
Attachment(s)  1) Notice of References Cited (PTO-892)  2) Notice of Draftsperson's Patent Drawing Review (PTO-948)	4) Interview Summary Paper No(s)/Mail Da						
<ul> <li>2) Motice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)</li> <li>Paper No(s)/Mail Date 0903 &amp; 1004.</li> </ul>		atent Application (PTO-152)					

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#### **DETAILED ACTION**

### Claim Objections

1. Claim 85 is objected to because "claim 86" at line 1 should read --claim 84--. Appropriate correction is required.

## Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 65, 66, 74, 75, and 84-88 are rejected under 35 U.S.C. 102(e) as being anticipated by US 6,780,704 B1 to Raaijmakers et al..

Regarding claim 65, the Raaijmakers et al. reference discloses a method of forming a MIS capacitor [abstract] on a semiconductor substrate (12) comprising the acts of: forming a semiconductive layer (i.e. HSG) over a substrate (12); forming a dielectric layer comprising aluminum oxide (col. 15, Table I) over said semiconductive layer by ALD [col. 15, lines 19-26]; and forming a metal nitride layer over said dielectric layer [col. 21, line 42 to col. 23, line 25].

Regarding claim 66, the semiconductive layer is formed of hemispherical grained polysilicon [col. 15, line 20].

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Regarding claim 74, the metal nitride layer is a titanium nitride layer formed by ALD [col. 22, lines 11-17].

Regarding claim 75, the TiN is formed by "ALD," therefore necessarily "using a nitrogen source and a titanium source precursor" [col. 22].

Regarding claim 84, the aluminum oxide dielectric layer is formed by ALD using an ozone source and an aluminum source precursor [col. 15].

Regarding claim 85, said aluminum source precursor is TMA col .15, line 22].

Regarding claim 86, the aluminum oxide dielectric layer is formed to a thickness of about 10 angstroms to about 500 angstroms [col. 14, lines 27-45].

Regarding claim 87, aluminum oxide dielectric layer is formed to a thickness of about 25 angstroms to about 100 angstroms [col. 14, lines 27-45].

Regarding claim 88, the aluminum oxide dielectric layer further comprises a material selected from the group consisting of tantalum oxide, zirconium oxide, hafnium oxide, hafnium-aluminum-oxygen alloys and lanthanum-aluminum-oxygen alloys [col. 21, lines 17-40].

## Allowable Subject Matter

- 3. Claims 92-103 are allowed.
- 4. Claims 67-73, 76-83 and 89-91 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.
- 5. The following is a statement of reasons for the indication of allowable subject matter:

Regarding claims 92-103, the prior art does not disclose an advantage of applicant's particular combination of forming HSG, forming a dielectric composite stack comprising aluminum oxide on the HSG and forming tungsten nitride over the dielectric composite stack.

Regarding claims 67-72, the prior art does not disclose the "act of opening the grains," only forming the grains to be open [].

Regarding claims 73, 76-80 and 82-83 the prior art teaches away from CVD by directing one to the advantage of ALD.

Regarding claim 81, the prior art does not discuss an advantage of particularly choosing tungsten nitride.

Regarding claims 89-91, the prior art does not disclose the particular combination of aluminum oxide and tantalum oxide as claimed.

#### Conclusion

6. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Evan Pert whose telephone number is 571-272-1969. The examiner can normally be reached on M-F (7:30AM-3:30 PM).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nathan Flynn can be reached on 571-272-1915. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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ETP

March 20, 2005

EVAN PERT
PRIMARY EXAMINER